# **Power MOSFET**

# 30 V, 0.9 m $\Omega$ , 303 A, Single N-Channel, SO-8FL

#### **Features**

- Small Footprint (5x6 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

## MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter		Symbol	Value	Unit	
Drain-to-Source Voltage		$V_{DSS}$	30	V	
Gate-to-Source Voltage			$V_{GS}$	±20	V
Continuous Drain Current $R_{\theta JC}$ (Notes 1, 3)	Steady	T <sub>C</sub> = 25°C	I <sub>D</sub>	303	Α
Power Dissipation $R_{\theta JC}$ (Notes 1, 3)	State	T <sub>C</sub> = 25°C	P <sub>D</sub>	134	W
Continuous Drain Current $R_{\theta JA}$ (Notes 1, 2, 3)	Steady	T <sub>A</sub> = 25°C	I <sub>D</sub>	47	Α
Power Dissipation $R_{\theta JA}$ (Notes 1, 2, 3)	State	T <sub>A</sub> = 25°C	P <sub>D</sub>	3.2	W
Pulsed Drain Current	T <sub>A</sub> = 25°	C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	552	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	-55 to 150	°C
Source Current (Body Diode)		I <sub>S</sub>	110	Α	
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 35 A)		E <sub>AS</sub>	862	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS (Note 1)

Parameter	Symbol	Value	Unit	
Junction-to-Case - Steady State	$R_{\theta JC}$	0.93	°C/W	
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	39		

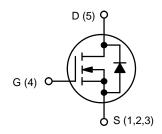
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- 3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



## ON Semiconductor®

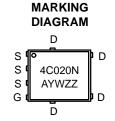
### www.onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
30 V	0.7 mΩ @ 10 V	202.4
30 V	1.0 mΩ @ 4.5 V	303 A



**N-CHANNEL MOSFET** 





Α = Assembly Location

= Year W = Work Week 77 = Lot Traceability

## **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>		
NTMFS4C020NT1G	SO-8FL (Pb-Free)	1500 / Tape & Reel		
NTMFS4C020NT3G	SO-8FL (Pb-Free)	5000 / Tape & Reel		

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

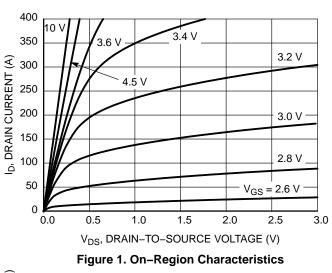
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•						
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				16.3		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 24 V	T <sub>J</sub> = 25 °C			1	μΑ
			T <sub>J</sub> = 125°C			100	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{G}$	<sub>S</sub> = 20 V			100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D = 250 \mu A$		1.3		2.2	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				5.8		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 30 A		0.6	0.7	
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 30 A		0.8	1.0	mΩ
Forward Transconductance	9FS	V <sub>DS</sub> = 3 V	I <sub>D</sub> = 30 A		183		S
Gate Resistance	$R_{G}$	T <sub>A</sub> = 25 °C			1.0		Ω
CHARGES AND CAPACITANCES							
Input Capacitance	C <sub>ISS</sub>				10144		pF
Output Capacitance	C <sub>OSS</sub>	V <sub>GS</sub> = 0 V, f = 1 MH	Hz, V <sub>DS</sub> = 15 V		5073		
Reverse Transfer Capacitance	C <sub>RSS</sub>				148		1
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 15 V; I <sub>D</sub> = 30 A			63		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>				18		
Gate-to-Source Charge	Q <sub>GS</sub>				29		
Gate-to-Drain Charge	$Q_{GD}$				13		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 15 V, I <sub>D</sub> = 30 A			139		nC
SWITCHING CHARACTERISTICS (Note 5)	•			•	•		•
Turn-On Delay Time	t <sub>d(ON)</sub>				29		
Rise Time	t <sub>r</sub>	Vgs = 4.5 V. Vns = 1	15 V. In = 15 A.		68		
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}, I_{D} = 15 \text{ A},$ $R_{G} = 3.0 \Omega$			53		ns
Fall Time	t <sub>f</sub>				36		
DRAIN-SOURCE DIODE CHARACTERISTIC	S						•
Forward Diode Voltage	V <sub>SD</sub>	VGS = 0 V,	T <sub>J</sub> = 25°C		0.73	1.1	V
			T <sub>J</sub> = 125°C		0.55		
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, dI}_{S}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 30 \text{ A}$			87		ns
Charge Time	ta				43		
Discharge Time	t <sub>b</sub>				44		
Reverse Recovery Charge	Q <sub>RR</sub>				147		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ .

5. Switching characteristics are independent of operating junction temperatures.

### TYPICAL CHARACTERISTICS



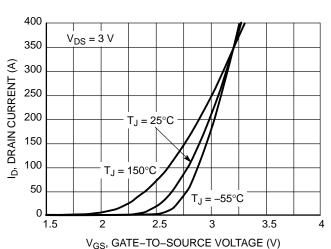


Figure 2. Transfer Characteristics

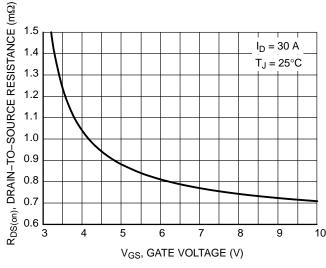


Figure 3. On-Resistance vs. Gate-to-Source Voltage

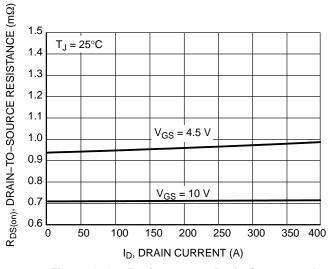


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

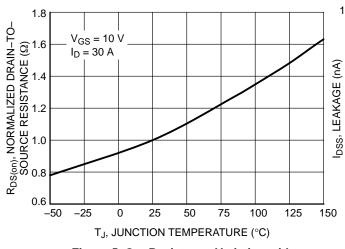


Figure 5. On–Resistance Variation with Temperature

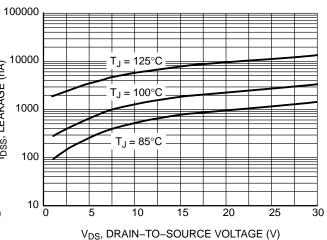


Figure 6. Drain-to-Source Leakage Current vs. Voltage

### TYPICAL CHARACTERISTICS

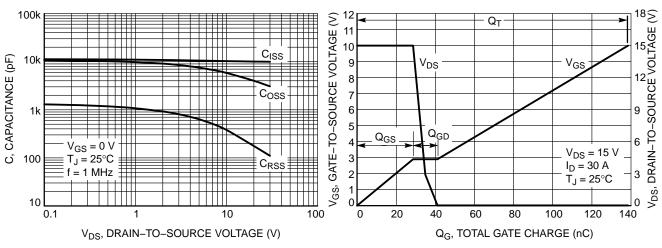


Figure 7. Capacitance Variation

Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

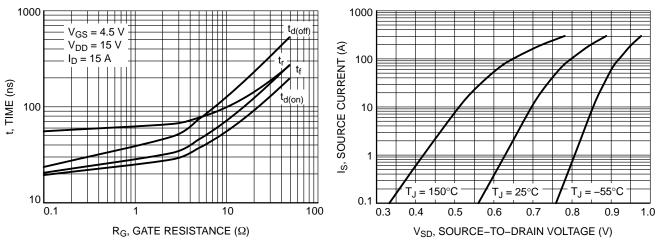


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

Figure 10. Diode Forward Voltage vs. Current

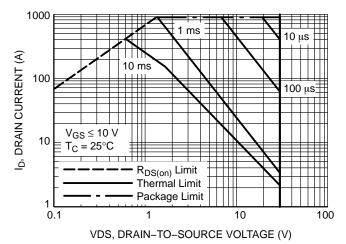


Figure 11. Maximum Rated Forward Biased Safe Operating Area

### **TYPICAL CHARACTERISTICS**

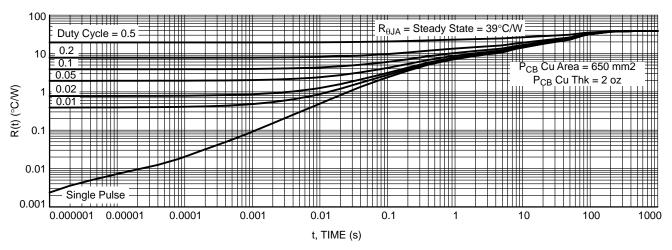


Figure 12. Thermal Impedance (Junction-to-Ambient)

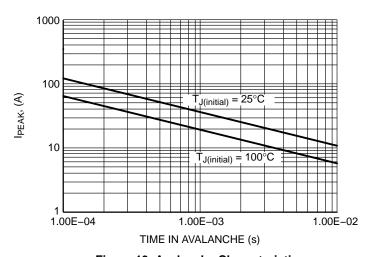
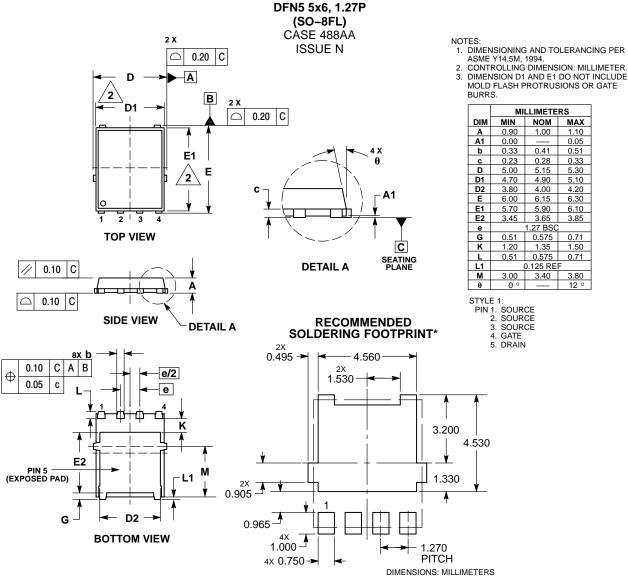


Figure 13. Avalanche Characteristics

#### PACKAGE DIMENSIONS



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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